NOTICE OF REVISION (NOR)

(See MIL-STD-480 for instructions)
This revision described below has been authorized for the document listed.

DATE (YY-MM-DD)

Form Approved OMB No.0704-0188

92-11-03

Public reporting burden for this collection is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden, to Washington Headquarters Services, Directorate for Information Operations and Reports, 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302, and to the Office of Information and Regulatory Affairs, Office of Management and Budget, Washington, DC 20503.

ORIGINATOR NAME AND ADDRESS Defense Electronics Supply Center Dayton, Ohio 45444-5277	2. CAGE CODE 67268	3. NOR NO. 5962-R009-93
	4. CAGE CODE	5.DOCUMENT NO.
	67268	5962-88509
6. TITLE OF DOCUMENT	7. REVISION LETTER	
MICROCIRCUIT, LINEAR, QUAD 12-BIT DIGITAL-TO-ANALOG CONVERTER, HYBRID	(Current) B	(New) C
	8. ECP NO. N. A.	

9. CONFIGURATION ITEM (OR SYSTEM) TO WHICH ECP APPLIES

ALL.

10. DESCRIPTION OF REVISION

Sheet 1: Revisions Itr column; add "C".

Revisions description column; add "Changes in accordance with NOR 5962-R009-93".

Revisions date column; add "92-11-03".

Revision level block; delete "B" and substitute "C".

Sheet 5: Tests, input current (high) and input current (low), conditions column, after "Pins 23 through 28"; add "8/", (TABLE I) (two places). Revision level block; delete "B" and substitute "C".

Test, input current (low), conditions column; change "V_{IN} = +5 V" to "V_{IN} = 0 V", (two places).

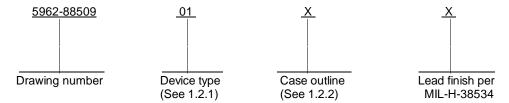
SHEET 7: Add note: "8/ The maximum limit for pin 24 is three times the specified maximum limit for pins 23, (TABLE I) 25, 26, 27, and 28." Revision level block; delete "B" and substitute "C".

11. THIS SECTION FOR GOVERNMENT USE ONLY

a. CHECK ONE [X]EXISTING DOCUMENT SUPPLEMENTED BY THIS NOR MAY BE USED IN MANUFACTURE.	[] REVISED DOCUMENT MUST BE RECEIVED BEFORE MANUFACTURER MAY INCORPORATE THIS CHANGE.	CUSTODIAN OF MASTER DOCUMENT SHALL MAKE ABOVE REVISION AND FURNISH REVISED DOCUMENT TO:
b. ACTIVITY AUTHORIZED TO APPROVE CHANGE FOR GOVERNMENT DESC-ECT	SIGNATURE AND TITLE Kendall A. Cottongim CHIEF,ELECTRONIC COMPONENTSBRANCH	DATE (YY-MM-DD) 92-11-03
12.ACTIVITY ACCOMPLISHINGREVISION	REVISION COMPLETED (Signature)	DATE (YY-MM-DD)
DESC-ECT	Gary Zahn	92-11-03

					RE	VIS	IONS	}										
LTR	DESCRIPTION					DA	TE (YR-	MO-DA	۸)		APPR	OVED)					
А	outline. Correct	Figure 1, change to side brazed package outline. Correct the maximum dimension for E1 and S. Editorial changes throughout.							89-01-10 M. A. Frye			!						
В		table I and	ct MIL-H-38534 processing. ble I and figures 1 and 2.						92-0	1-13		Alan Barone			е			
REV SHEET REV SHEET																		
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- 1. SCOPE
- 1.1 <u>Scope</u>. This drawing describes device requirements for class H hybrid microcircuits to be processed in accordance with MIL-H-38534.
 - 1.2 Part or Identifying Number (PIN). The complete PIN shall be as shown in the following example:



1.2.1 <u>Device type(s)</u>. The device type(s) shall identify the circuit function as follows:

<u>Device type</u>	Generic number	Circuit function
01	AD390S	Quad 12 bit DAC (bipolar)
02	AD390T	Quad 12 bit DAC (bipolar)

1.2.2 <u>Case outline(s)</u>. The case outline(s) shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter

Case outline

X See figure 1 (28-lead, 1.414" x .610" x .225"), dual-in-line package

1.3 Absolute maximum ratings.

V_{CC} to DGND range -----V_{EE} to DGND range ----Digital inputs (pins 1-12 and 23-28) to DGND ---V_{REFIN} to AGND ----AGND to DGND ----0 V dc to +18 V dc 0 V dc to -18 V dc -1.0 V dc to +7 V dc V_{EE} to V_{CC} Outputs (pins 16, 18, 19, 20, 21): Shorted to AGND or DGND-----Indefinite Shorted to (V_{CC} or V_{EE})------Storage temperature range Momentary 65° C to +150° C Lead temperature (soldering, 10 seconds) - - - - -+300°C Junction temperature (T_J)------+175°C Thermal resistance, junction-to-case (Θ_{JC}) - - - - Thermal resistance, junction-to-ambient (Θ_{JA})- - - -8°C/W 25° C/W

1.4 Recommended operating conditions.

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE **5962-88509**REVISION LEVEL B SHEET **2**

2. APPLICABLE DOCUMENTS

2.1 <u>Government specifications and standard</u>. Unless otherwise specified, the following specifications and standard of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATIONS

MILITARY

MIL-M-38510 MIL-H-38534 - Microcircuits, General Specification for.

- Hybrid Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

- Test Methods and Procedures for Microelectronics.

(Copies of the specifications, and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
 - 3. REQUIREMENTS
- 3.1 <u>Item requirements</u>. The individual item requirements shall be in accordance with MIL-H-38534 and as specified herein.
- 3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-H-38534 and herein.
 - 3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.2 herein.
 - 3.2.2 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 2.
 - 3.2.3 Truth tables(s). The truth tables(s) shall be as specified on figure 3.
 - 3.2.4 Timing waveform(s). The timing waveform(s) shall be as specified on figure 4.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.
- 3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.
- 3.5 <u>Marking</u>. Marking shall be in accordance with MIL-H-38534. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in QML-38534 (see 6.6 herein).
- 3.6 <u>Manufacturer eligibility</u>. In addition to the general requirements of MIL-H-38534, the manufacturer of the part described herein shall submit for DESC-ECT review and approval electrical test data (variables format) on 22 devices from the initial quality conformance inspection group A lot sample, produced on the certified line, for each device type listed herein. The data should also include a summary of all parameters manually tested, and for those which, if any, are guaranteed.
- 3.7 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in QML-38534 (see 6.6 herein). The certificate of compliance submitted to DESC-ECT prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-H-38534 and the requirements herein.
- 3.8 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-H-38534 shall be provided with each lot of microcircuits delivered to this drawing.

STANDARDIZED MILITARY DRAWING	SIZE A		5962-88509
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL B	SHEET 3

- 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-H-38534.
- 4.2 <u>Screening</u>. Screening shall be in accordance with MIL-H-38534. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.7 herein).
 - (2) T_A as specified in accordance with table I of method 1015 of MIL-STD-883.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 <u>Quality conformance inspection</u>. Quality conformance inspection shall be in accordance with MIL-H-38534 and as specified herein.
 - 4.3.1 Group A inspection. Group A inspection shall be in accordance with MIL-H-38534 and as follows:
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 7 and 8 shall include verification of the truth table.
 - 4.3.2 Group B inspection. Group B inspection shall be in accordance with MIL-H-38534.
 - 4.3.3 Group C inspection. Group C inspection shall be in accordance with MIL-H-38534 and as follows:
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.7 herein).
 - (2) T_A as specified in accordance with table I of method 1005 of MIL-STD-883.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.
 - 4.3.4 <u>Group D inspection</u>. Group D inspection shall be in accordance with MIL-H-38534.

STANDARDIZED MILITARY DRAWING	SIZE A		5962-88509
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL B	SHEET 4

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions 1/	Device	Group A	Lin	nits	Unit
		-55° C ≤ T _A ≤ +125° C unless otherwise specified	types	subgroups	Min	Max	
Input voltage (high)	V _{IH}	Pins 1 through 12	All	1 2, 3 <u>2</u> /	2.0		V
		Pins 23 through 28	All	1, 2, 3 <u>2</u> /	2.0		+
Input voltage (low)	V _{IL}	Pins 1 through 12	All	1 2, 3 <u>2</u> /		0.8	V
		Pins 23 through 28	All	1, 2, 3 <u>2</u> /		0.8	
Input current (high)	Ін	V _{IN} = +5 V Pins 1 through 12	All	1 2, 3 <u>2</u> /		1200	μА
		V _{IN} = +5 V Pins 23 through 28	All	1, 2, 3 <u>2</u> /		1200	
Input current (low)	I _{IL}	V _{IN} = +5 V Pins 1 through 12	All	1 2, 3 <u>2</u> /		400	μА
		V _{IN} = +5 V Pins 23 through 28	All	1, 2, 3 <u>2</u> /		400	
Output voltage range	V _{OUT}	External +10.000 V ref <u>3</u> /	All	1, 2, 3	-10	+10	V
Gain error	Ae	External +10.000 V ref BC = 111111111111 End-point electrical	01 02 All	4 4 4	1 05 2	+.1 +.05 +.2	% FSR <u>4</u> /
Gain error temperature coefficient	T _{C/Ae}	External +10.000 V ref BC = 111111111111	01 02	5, 6 5, 6	-10 -5	+10 +5	ppm/° C
Offset error	V _{OS}	External +10.000 V ref BC = 000000000000 End-point electrical	01 02 All	1 1 1	05 025 1	+.05 +.025 +.1	% FSR <u>4</u> /

See footnotes at end of table.

STANDARDIZED MILITARY DRAWING	SIZE A		5962-88509
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL B	SHEET 5

TABLE I. <u>Electrical performance characteristics</u> - Continued.

Test	Symbol	Conditions 1/	Device	Group A	Lin	nits	Unit
		-55° C ≤ T _A ≤ +125° C unless otherwise specified	types	subgroups	Min	Max	
Bipolar zero temperature coefficient	T _{C/BPZ}	V _{BPFS} = ±10 V <u>5</u> /	01 02	2, 3 2, 3	-10 -5	+10 +5	ppm/°C
Differential linearity error	DLE	6/ End-point electrical	01 02 All All	1 1 2, 3 1	75 5 -1 -1	+.75 +.5 +1 +1	LSB
Integral linearity error 7/	LE	End-point electrical	01 02 All	1, 2, 3 1, 2, 3 1	75 5 -1	+.75 +.5 +1	LSB
Power supply voltages	v _{cc}	<u>3</u> /	All	1, 2, 3	+13.5	+16.5	V
	V _{EE}		All	1, 2, 3	-16.5	-13.5	
Power supply current	I _{CC}	Data input	All	1	-100	0	mA
(negative)		bits = 111111111111 No load		2, 3 <u>2</u> /	-120	0	
Power supply current	I _{EE}	Data input	All	1		35	mA
(positive)		bits = 11111111111 No load		2, 3 <u>2</u> /		35	
Power supply gain	PSRR	Data input	All	_1	006	+.006	% FS
sensitivity gain/ ±V _S (+V _{CC} and -V _{EE})		bits = 11111111111 ±V _S = ±15 V ±10%		2, 3 <u>2</u> /	006	+.006	per %
Functional tests		See 4.3.1b	All	7, 8			
Chip select pulse width 2/	t _{AW}	See figure 4	All	9, 10, 11	100		ns
Address select low time $\underline{2}/$	t _{WP}	See figure 4	All	9, 10, 11	100		ns

See footnotes at end of table.

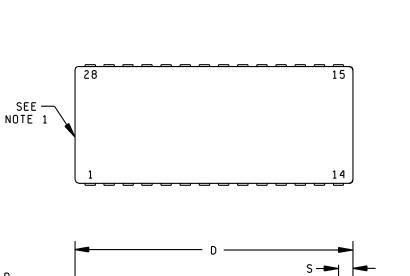
STANDARDIZED MILITARY DRAWING	SIZE A		5962-88509
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL B	SHEET 6

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions 1/			Lim	Unit	
		-55° C ≤ T _A ≤ +125° C unless otherwise specified	types	subgroups	Min	Max	
Data valid before AO rising edge 2/	t _{DW}	See figure 4	All	9, 10, 11	50		ns
Data valid after AO rising edge 2/	t _{DH}	See figure 4	All	9, 10, 11	10		ns
Chip sele <u>ct</u> valid before A1 low 2/	t _{AS}	See figure 4	All	9, 10, 11	0		ns
Settling time 2/	t _{SETT}	See figure 4	All	9, 10, 11		8	μs

- $\frac{1}{2}$ V_{CC} = +15 V, V_{EE} = -15 V. Parameter shall be tested as part of device initial characterization and after design and process changes. Parameter shall be guaranteed to the limits specified in table I for all lots not specifically tested.
- Verified as test condition while testing other parameters.
- Full scale range = 20 V for a ±10 V bipolar range. Full scale range = 10 V for a 0 V to +10 V unipolar
- Bipolar zero = (BC 10000000000) (BC = 00000000000).
- Monotonicity is tested over the full military temperature range.
- Integral nonlinearity is a measure of the maximum deviation from a straight line passing through the end points of the transfer function.

STANDARDIZED MILITARY DRAWING	SIZE A		5962-88509
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL B	SHEET 7



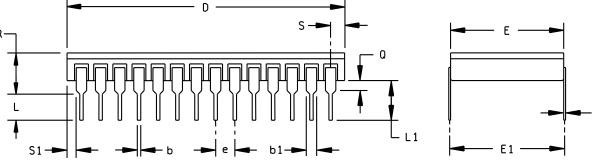


FIGURE 1. Case outline (all device types).

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-88509
		REVISION LEVEL B	SHEET 8

	Inches		Millimeters		
Symbol	Min	Max	Min	Max	Notes
A		.225		5.72	
b	.014	.023	0.36	0.58	
b1	.030	.070	0.76	1.78	2
C	.008	.015	0.20	0.38	
D	.000	1.414	0.20	35.92	
E	500		14 72		
	.580	.610	14.73	15.49	
<u>E1</u>	.590	.620	14.99	15.75	6
е	.100 E	BSC	2.54 B	SC	4, 7
L	.120	.200	3.05	5.08	
L1	.180		4.57		
Q	.015	.075	0.38	1.90	3
S		.098		2.49	5
S1	.005		0.13		5

NOTES:

- 1. Index area; a notch or a lead one identification mark is located adjacent to lead one.
- The minimum limit for dimension b1 may be .023 (0.58 mm) for all four corner leads only.
 Dimension Q shall be measured from the seating plane to the base plane.

- 4. The basic pin spacing is .100 (2.54 mm) between centerlines.
 5. Applies to all four corners.
 6. E1 shall be measured at the centerline of all the leads (at stand off).
- 7. Twenty six spaces.

FIGURE 1. Case outline (all device types) - Continued.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-88509
		REVISION LEVEL B	SHEET 9

Device types	All
Case outline	X
Terminal number	Terminal connection
1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 10 20 21 22 23 24 25 26 27 28	DBO (LSB) DB1 DB2 DB3 DB4 DB5 DB6 DB7 DB8 DB9 DB10 DB11 (MSB) DGND VEE AGND REF OUTPUT REF INPUT VOUT1 VOUT2 VOUT3 VOUT4 VCC A1 A0 CS1 CS2 CS3 CS4

FIGURE 2. <u>Terminal connections (all device types)</u>.

STANDARDIZED
MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

SIZE A		5962-88509
	REVISION LEVEL B	SHEET 10

Digital input code	Analog output voltage
0000 0000 0000	-10.000 V -Full scale
0100 0000 0000	-5.000 V -1/2 scale
1000 0000 0000	0.000 V Zero
1000 0000 0001	+4.88 mV +1 LSB
1100 0000 0000	+5.000 V +1/2 scale
1111 1111 1111	+9.9951 V +Full scale - 1 LSB

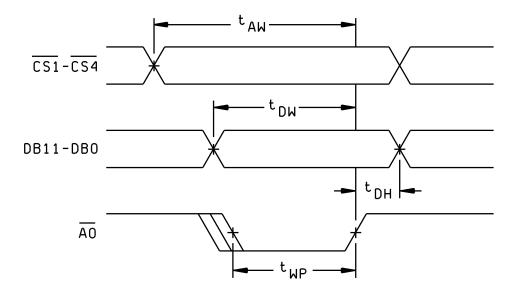
CS1	CS2	CS3	CS4	A1	A0	Operation
1 X	1 X	1 X	1 X	X 1	X 1	No operation No operation
0 1 1 1	1 0 1 1	1 1 0 1	1 1 1 0	1 1 1	0 0 0 0	Enable 1st rank of DAC 1 Enable 1st rank of DAC 2 Enable 1st rank of DAC 3 Enable 1st rank of DAC 4
0 1 1 1	1 0 1 1	1 1 0 1	1 1 1 0	0 0 0 0		Load DAC 1 second rank from first rank Load DAC 2 second rank from first rank Load DAC 3 second rank from first rank Load DAC 4 second rank from first rank
0	0	0	0	0	0	All latches transparent

FIGURE 3. Truth table (all types).

STANDARDIZED MILITARY DRAWING	SIZE A	
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISIO

DEVICE TYPES 01 AND 02

WRITE CYCLE NUMBER 1 (LOAD FIRST RANK FROM DATA BUS: $\overline{A1} = 1$)



WRITE CYCLE NUMBER 2 (LOAD SECOND RANK FROM FIRST RANK: $\overline{AO} = 1$)

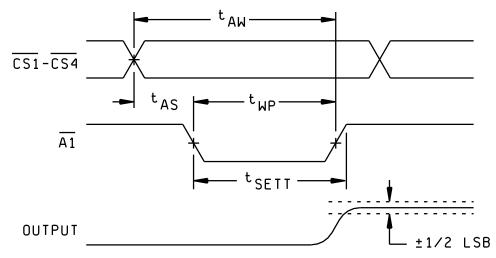


FIGURE 4. Timing waveforms.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-88509
		REVISION LEVEL B	SHEET 12

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5008, group A test table)
Interim electrical parameters	1, 4
Final electrical test parameters	1*, 2, 3, 4, 5, 6, 7, 9
Group A test requirements	1, 2, 3, 4, 5, 6, 7, 8, 9, 10, 11
Group C end-point electrical parameters	1, 4

^{*} PDA applies to subgroup 1.

- 5. PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-H-38534.
- 6. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for original equipment design applications and logistic support of existing equipment.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).
- 6.4 <u>Record of users</u>. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-ECT, telephone (513) 296-6047.
- 6.5 <u>Comments</u>. Comments on this drawing should be directed to DESC-ECT, Dayton, Ohio 45444, or telephone (513) 296-5374.
- 6.6 <u>Approved sources of supply</u>. Approved sources of supply are listed in QML-38534. Additional sources will be added to QML-38534 as they become available. The vendors listed in QML-38534 have agreed to this drawing and a certificate of compliance (see 3.7 herein) has been submitted to and accepted by DESC-ECT.

STANDARDIZED		
MILITARY DRAWING		
DEFENSE ELECTRONICS SUPPLY CENTER		
DAYTON, OHIO 45444		

SIZE A		5962-88509
	REVISION LEVEL B	SHEET 13

STANDARDIZED MILITARY DRAWING SOURCE APPROVAL BULLETIN

DATE: 92-01-13

Approved sources of supply for SMD 5962-89594 are listed below for immediate acquisition only and shall be added to QML-38534 during the next revision. QML-38534 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DESC-ECT. This bulletin is superseded by the next dated revision of QML-38534.

Standardized military drawing PIN	Vendor CAGE number	Vendor similar PIN <u>1</u> /
5962-8850901XX	51640	AD390SD/883B
5962-8850902XX	51640	AD390TD/883B

1/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number Vendor name and address

51640

Analog Devices Micro Electronics Division 829 Woburn Street Wilmington, MA 01887

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in this information bulletin.